# MPW2 testing in the RBI Microbeams

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#### **Presentation**

- Ion Microbeam testing of the MPW2 monolithic detector chip
  - Ion Microbeam Facility (Ruder Boskovic Institute, Zagreb, Croatia)
  - Description of an Ion Microbeam test
  - Single Event Effects in Memory Cells
  - Charge Collection Efficiency in Monolithic Detectors
  - Prospective

Disclaimer: The first testbeam was along past week, June 14th to 18th 2021

It is still work in progress

#### Description of an Ion Microbeam Experiment

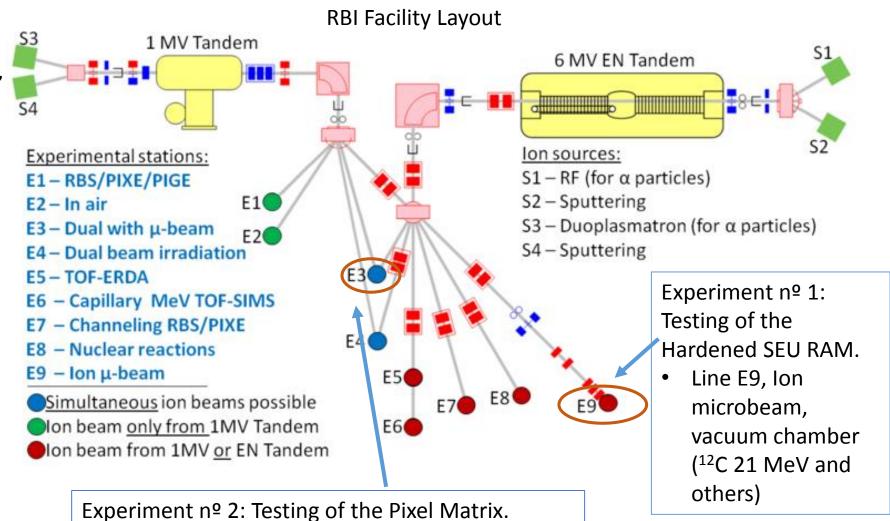
- An ion microbeam designates a low-medium energy hadron accelerator (1 -200 MeV), fixed target, with end station focusing capabilities (1-40 μm² tipically, even less)
- The beam can be defocused (up to a mm<sup>2</sup>) or strongly focused by magnetic/electrostatic lenses.
- The flux is selectable from 100 ions/sec to more than 10E6 ions/sec
- The beam operates in fixed spot or in scanning modes (zig-zag, fan, etc).

  Master equation:

E/Ma\/\ =\//1 | a\

E(MeV) = V(1+q)

where V is the accelerating voltage and q is the charge state of the ion. Ex. for protons, the RBI 6MV tandem accelerator gets a theoretical máximum of 7 MeV



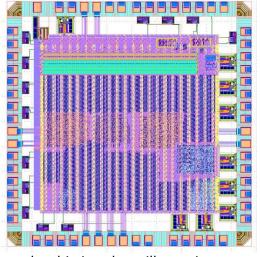
Line E3, proton microbeam, in air (2 MeV)

#### **Ion Range in Target**

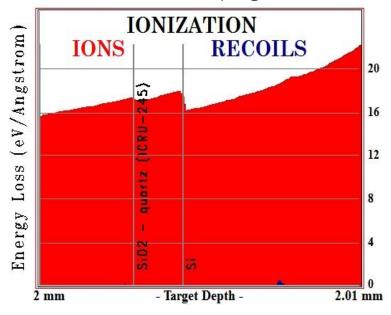
For every target block we need to know:

- 1. The set of (ions, energy) really available in the facility (accelerators are whimsical beasts)
- 2. Mapping the number of metallization and passivation layers really used in the target chip
- 3. The thickness and material of every layer (from Design Technology Kit documents, always under NDA)
- 4. A full set of Montecarlo simulations to predict range and LET in the active volumes (for SEE) or in the detector volumen (segmented

detectors)

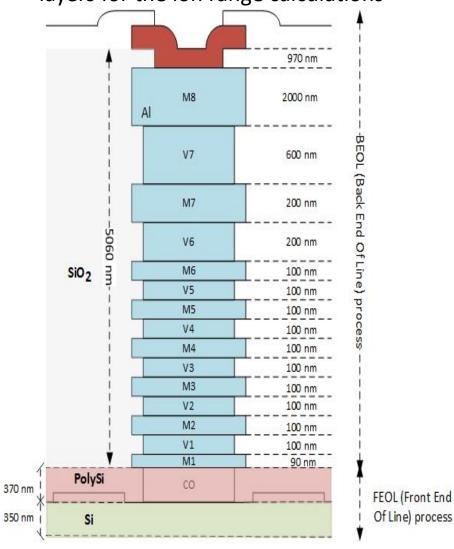


the chip is only an illustration



38<sup>th</sup> RD50 Workshop, June 21<sup>st</sup>-23<sup>rd</sup> 2021

Classification of the different metallization layers for the ion range calculations

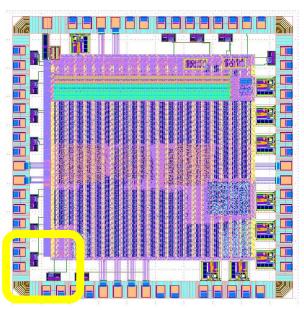


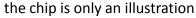
due to industry confidential reasons, the shown stack is only a representation, not the real Lfoundry 150nm one

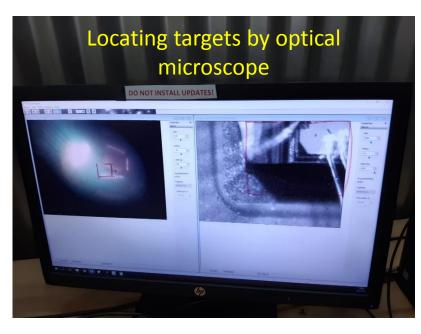
#### **Beam Targeting**

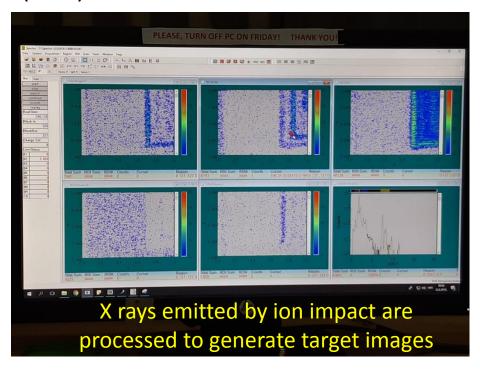
#### **Target Location means**

- Locating chip surface structures for XY coordinate frame determination, finding a coordinates origin and geographical waypoints for beam positioning.
- 2. Selecting the appropriate ion & energy set considering the cross-section of every target.
- Coarse finding the XY positions by microscope optical inspection/local scintillation light (if possible)
- 4. Precise location of XY waypoints by Particle Induced X ray Emission (PIXE)









#### Testbeams #1 and #2

#### MPW2 RD50 Test chip

#### Testbeam #1

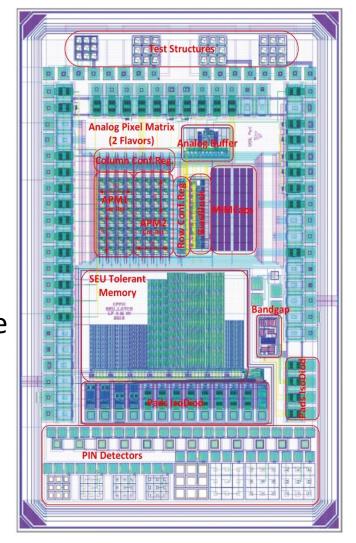
**SEU Sensitivity Analysis** 

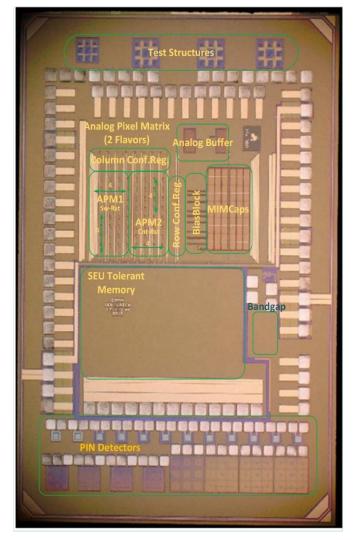
• We look for Single Event Upsets in the SEU tolerant memory cells. The objective is to have a SEU sensitivity map.

#### **Testbeam #2**

Pixel Charge Collection Efficiency

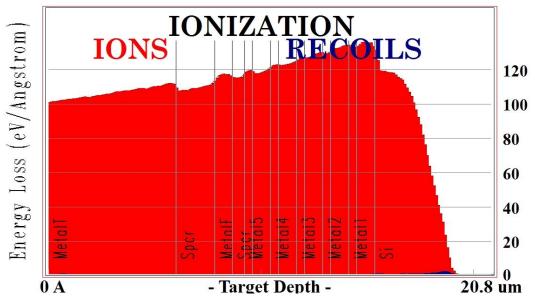
• The 8x8 pixel matrix has no addressable readout blocks so for a Charge Collection Efficiency analysis the beam make the addressing by physical aiming at every pixel.



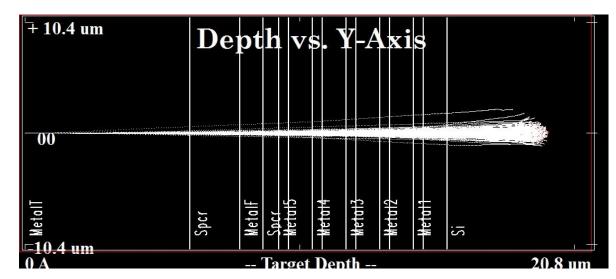


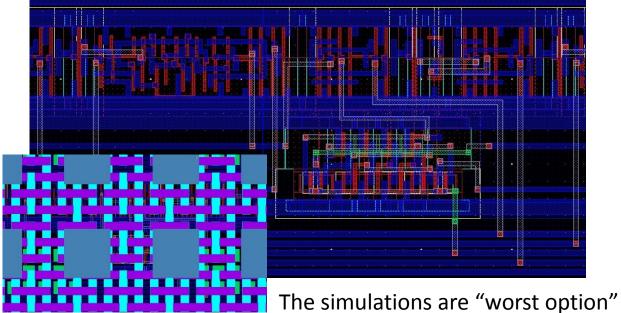
#### **Exp#1: SRIM Simulations**

120 eV/Angstrom translates into LET ~5 MeV-cm<sup>2</sup>/mg



- Li 3+ 14 MeV gives 30 eV/Ang (1.28 MeV-cm2/mg), Boron 17.5 MeV gives 90 eV/Ang (4.4 MeV-cm2/mg), low under Carbon ions, C5+. Oxygen O6+ 24.5 MeV reaches the active volume but gives only 30 eV/Ang there, same as Li3+. C5+ 17.3 MeV gives 40 eV/Ang so it is the starting point for aiming.
- We chose <sup>12</sup>C 5+ ions at 20 MeV because they can deposit enough energy in the transistors active volume and can range deep into the memory cell, LET ~ 5 MeV-cm<sup>2</sup>/mg





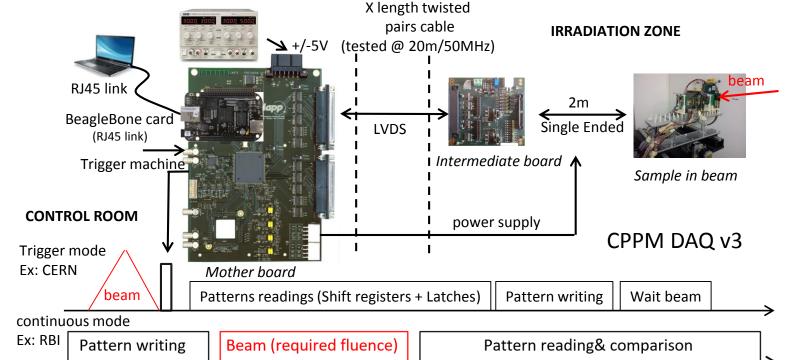
to consider filling density layers

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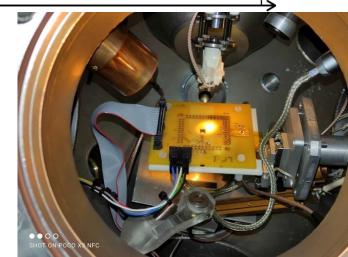
#### Exp#1: DAQ system and general layout







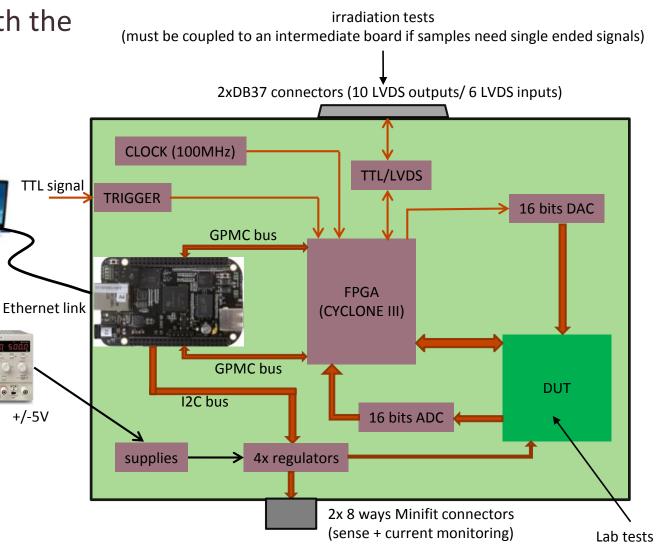
**General Layout**: The target MPW2 chip is inside the microbeam vacuum chamber, connected with flat ribbon cables to the external DAQ. The CPPM DAQ v3 operates in continuous mode. The X ray detector in the chamber monitors the PIXE emission continuously.



# Exp#1: DAQ system and general layout

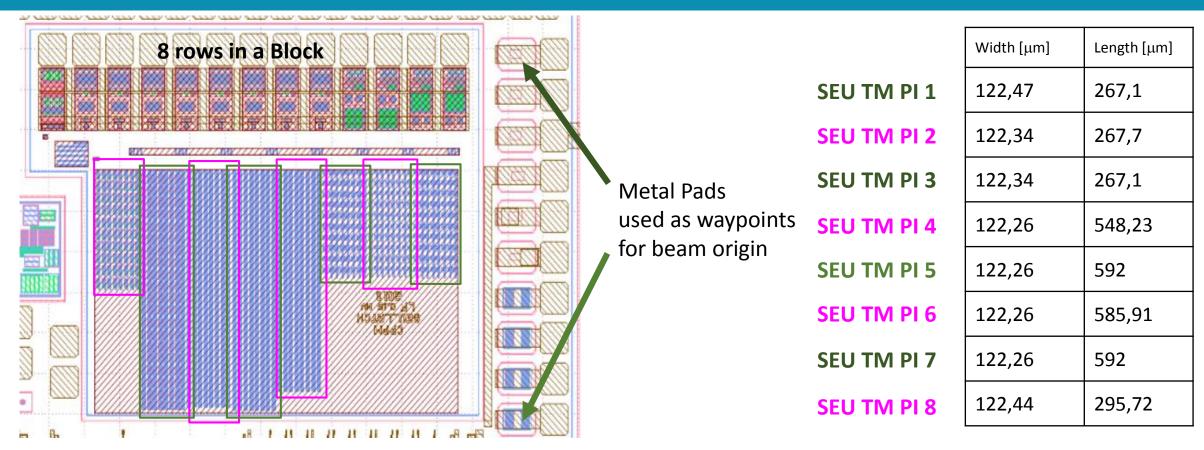
 Mother board designed in collaboration with the **IN2P3** Annecy laboratory Features: require +5 V (3A) / -5V (100mA) nanoPC BeagleBone card + FPGA

- - Connected via GPMC bus
  - Flexible programing
  - 40 TTL signals
  - 30 LVDS signals
  - Analog channels available
    - 4 channels SAR ADC's 16 bits (ADS8568 TI)
    - 10 DAC's 16 bits (DAC8830 TI)
  - 4 programmable regulators
    - 2 x LT 3021
    - 2 x LT 3026 (up to 1,5 A)
      - Must be tested
  - Monitoring:
    - °C: MAX31865 (RTD-digital converter)
    - current supply: MAX611
- Lab tests (local mode)
- irradiation tests (remote mode via LVDS signals)



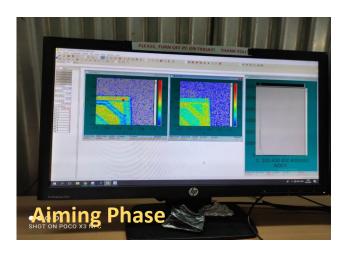
For the lasted version

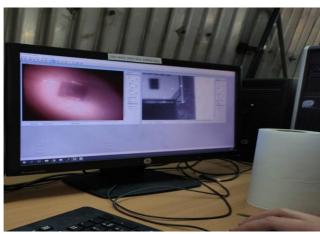
#### Exp#1: MPW2 memory flavours

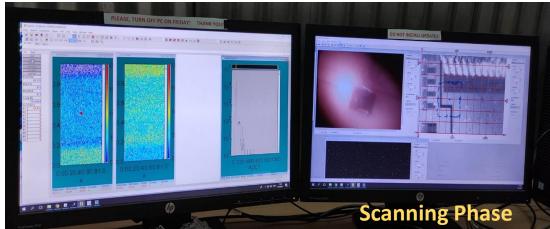


- Col1: Standard Cells
- Col2: DICE Latch "Dual Interlocked Storage Cell"
- Col3: Enhanced DICE Latch
- Col4 : Triple redundancy standard cells

- Col5 : Triple redundancy DICE latch
- Col6 :Split Triple redundancy with standard cells
- Col7: Split Triple redundancy with DICE cells
- Col8 : SRAM

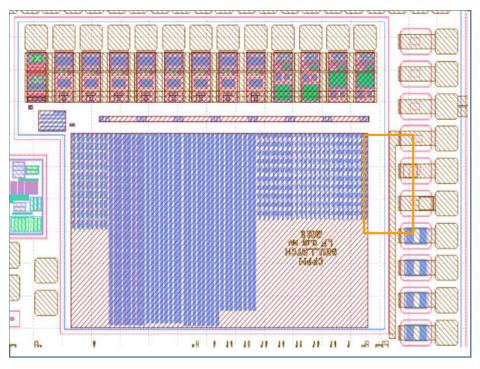




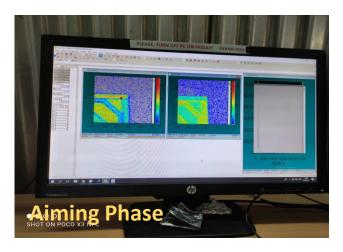


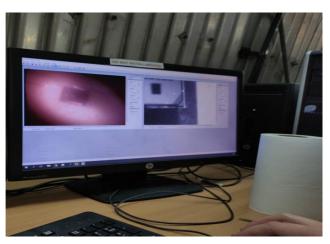
The aiming phase and the scanning phase made with  $^{12}$ C ions 20 MeV ( $^{\sim}4.8$  MeV-cm2/mg in this structure), Beam Spot 10  $\mu$ m<sup>2</sup>

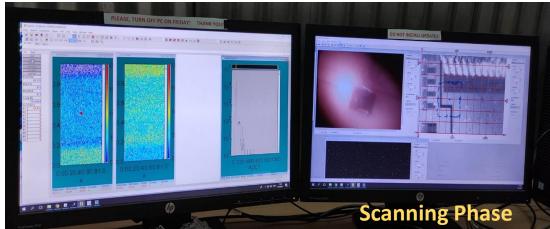




Flux: 4E6 ions/cm<sup>2</sup>-sec

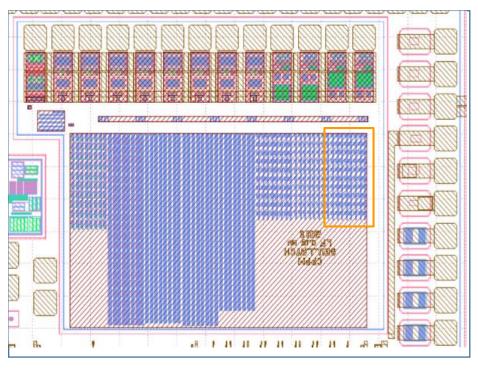




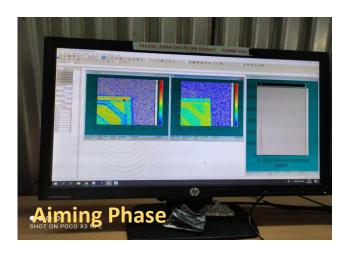


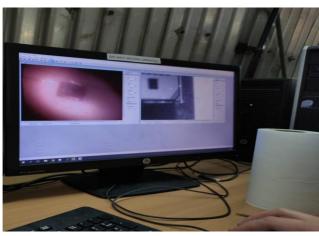
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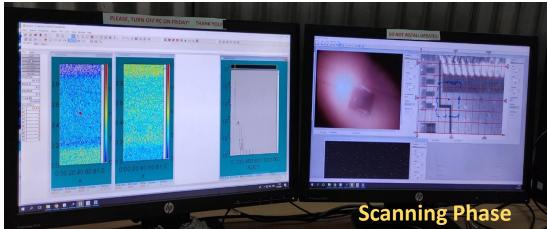




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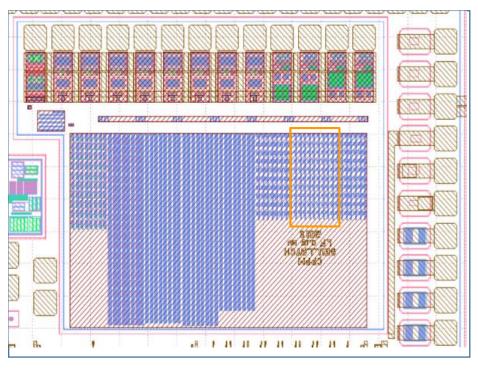




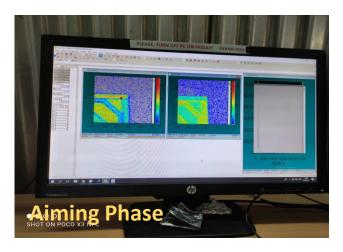


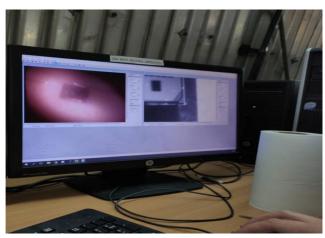
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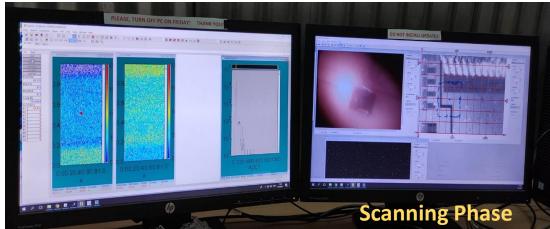




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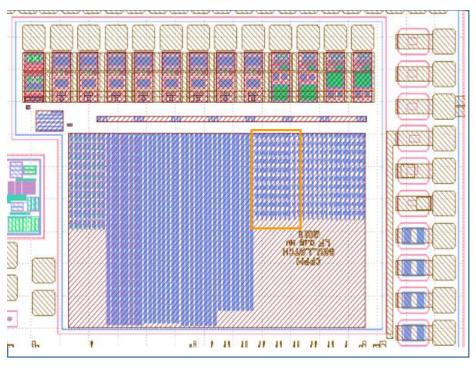




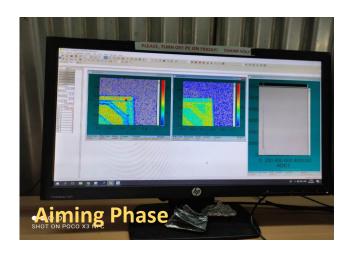


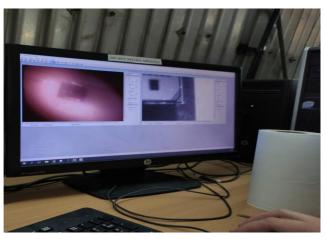
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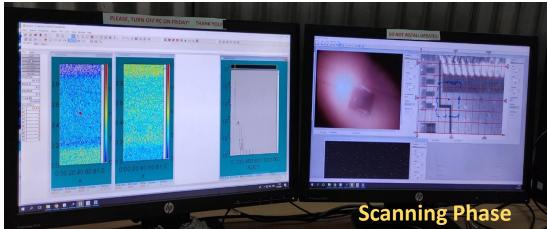




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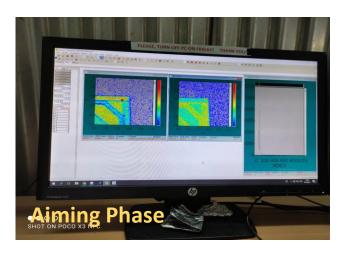


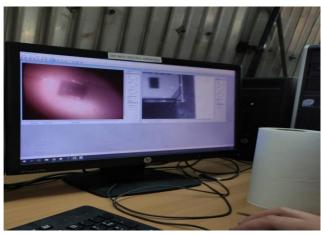
Scanning area (135 x 270)  $\mu$ m x 2.6 and X <sub>calibration</sub> = 0.32 x 10 => 175.5 x 702  $\mu$ m

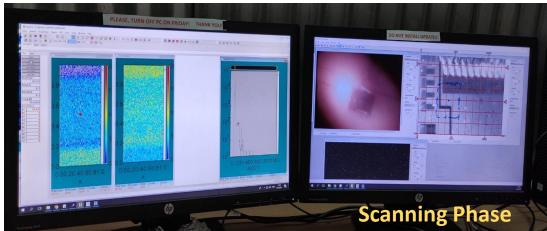
Map size: 128 x 128 pixels



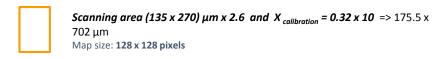
Flux: 4E6 ions/cm<sup>2</sup>-sec

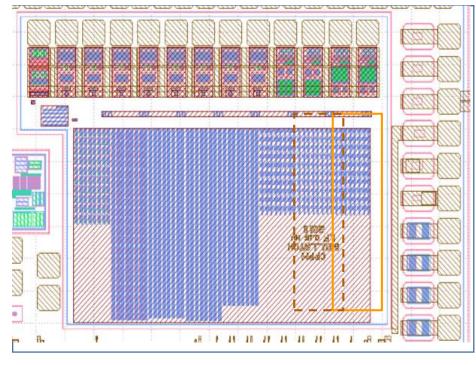




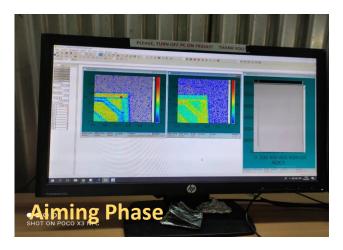


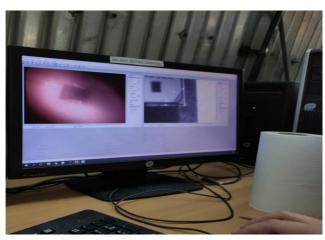
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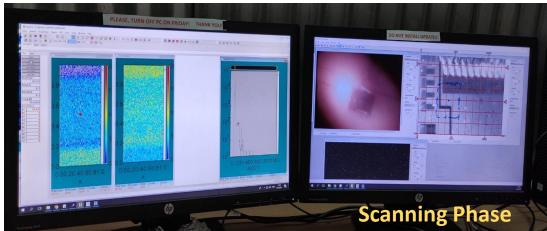




Flux: 4E6 ions/cm<sup>2</sup>-sec





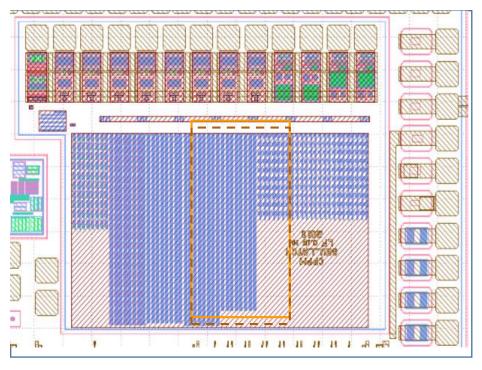


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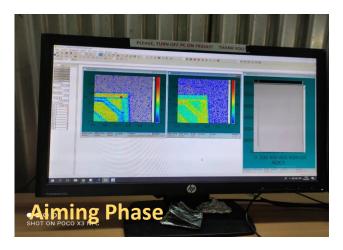


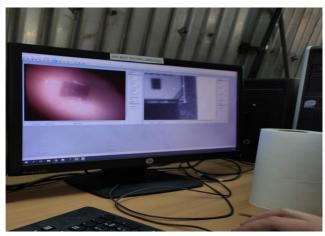
Scanning area (135 x 270)  $\mu m$  x 2.6 and X  $_{calibration}$  = 0.64 x 10  $\,$  => 351 x 702  $\mu m$ 

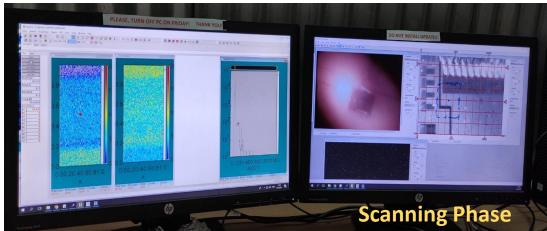
Change in the map size: 256 x 256 pixels



Flux: 4E6 ions/cm<sup>2</sup>-sec

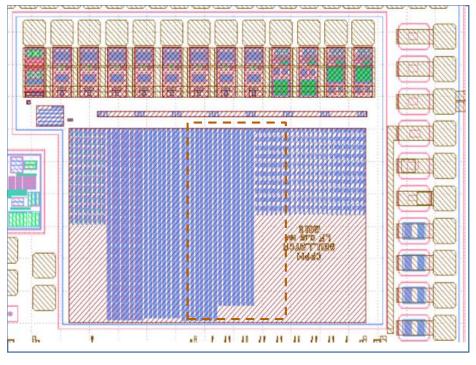




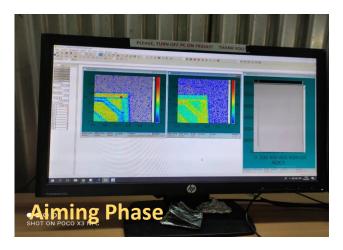


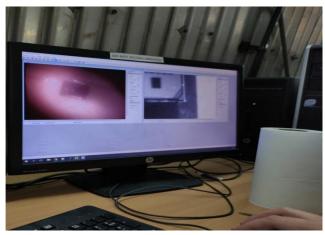
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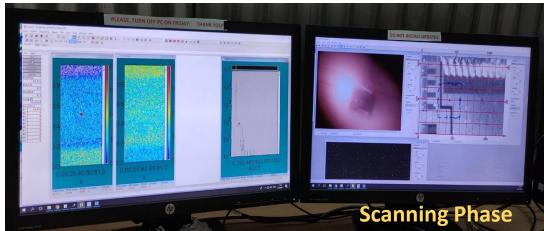




Flux: 4E6 ions/cm<sup>2</sup>-sec





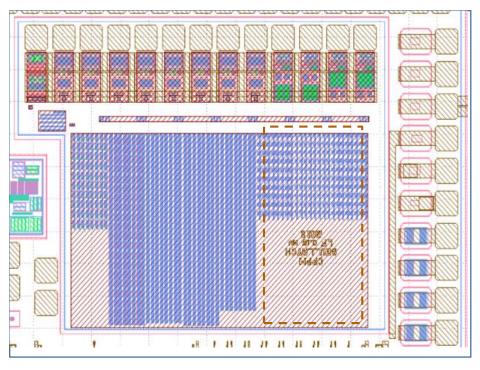


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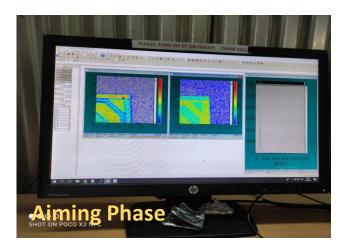


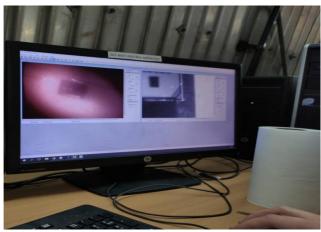
Scanning area (135 x 270)  $\mu$ m x 2.6 and X  $_{calibration}$  = 0.64 x 10 => 351 x 702  $\mu$ m

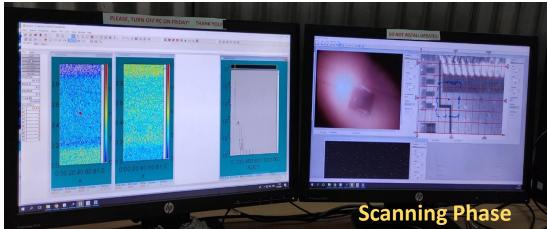
Change in the map size: 256 x 256 pixels



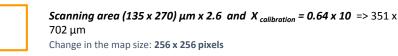
Flux: 4E6 ions/cm<sup>2</sup>-sec

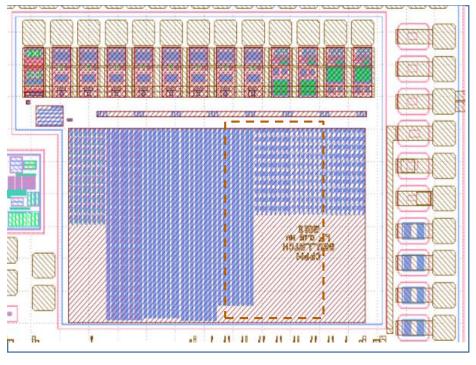






The aiming phase and the scanning phase made with  $^{12}$ C ions 20 MeV ( $^{\sim}4.8$  MeV-cm2/mg in this structure), Beam Spot 10  $\mu$ m<sup>2</sup>





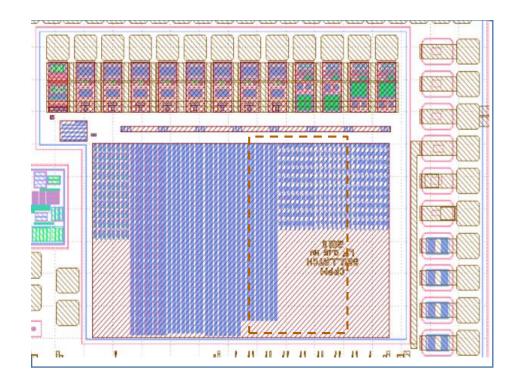
Flux: 4E6 ions/cm<sup>2</sup>-sec

#### **Observed SEUs in:**

- Col1: Standard Cells (after 60-600 sec of scanning)
- Col2: DICE Latch "Dual Interlocked Storage Cell"
- Col3: Enhanced DICE Latch

#### No observation of SEUs (after 44 min of scanning):

- Col4: Triple redundancy standard cells
- Col5-8: Not scanned in this experimental run



Further data analysis under way at the moment

#### **Exp#2 General Layout**

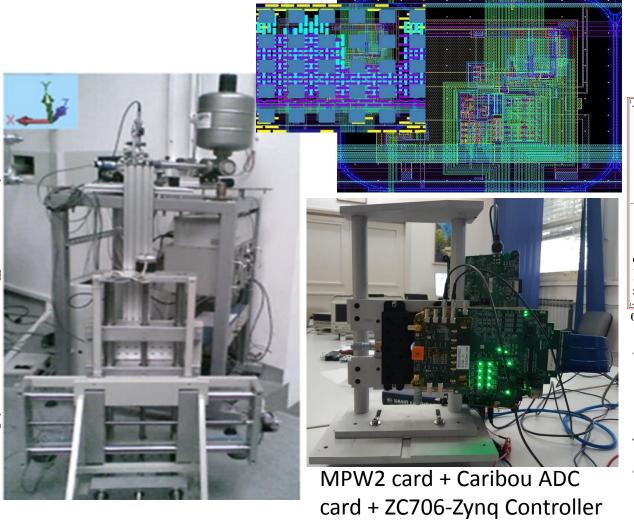
-For the Pixel CCE we use the external microbeam line fed by the Tandem accelerator (2 MeV protons, around 1.5 MeV when in air)

-Protons 1.5 MeV means LET ~0,25 MeV-cm²/mg, enoughfor a particle detector (1 GeV proton has a LET ~0,0018 MeV-cm²/mg)

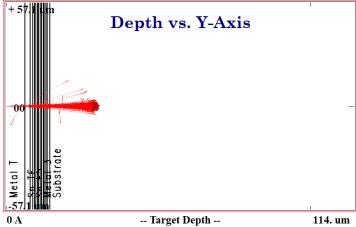
-The microbeam can be spot focused up to 30  $\mu m^2$  Pixel area is ~60x60  $\mu m^2$ 

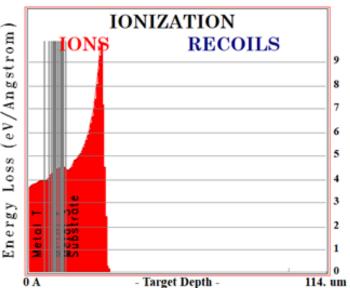
-Step by Step beam scanning mode

-No need of vacuum so a great simplification in the experiment layout



Protons 1.5 MeV can go through metal/passivation layers and reach the pixel detector active volume

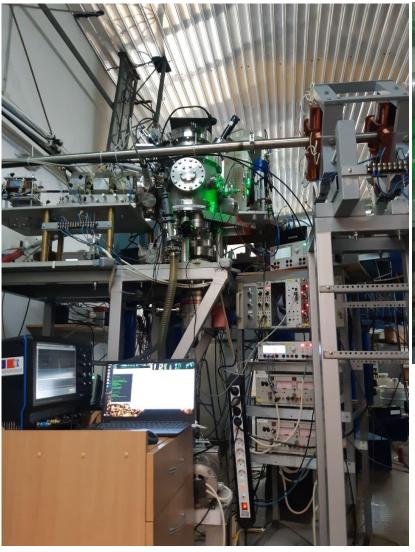




Card + Graphical User Interface

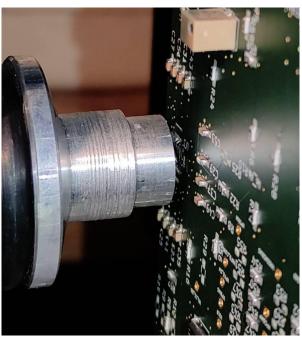
in a nearby laptop

# **Exp#2 General Layout**









- The MPW2 chip and DAQ setup (Caribou and ZC706 cards) are placed on a holder in front of the external microbeam outport window.
- The DAQ system Works properly, we need more chips
- Beam window availability very soon next month

#### Conclusions

- The SEE experiment showed SEU events in several columns
- The CCE pixel experiment is in standby waiting for beam opportunity
- The microbeam approach is useful for SEE Sensitivity Maps and for Physical Addressing detector pixel matrices (a form of IBIC/TRIBIC experiment)
- Future improvements at the RBI facility will make this testbeams even better

#### The End

# Thanks for your attention! fpalomo@us.es pangaud@cppm.in2p3.fr aneliya.karadzhinova@helsinki.fi jaksic@irb.hr





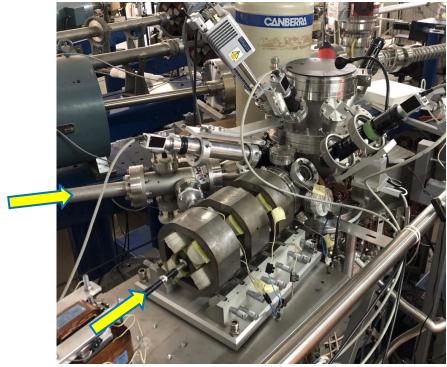


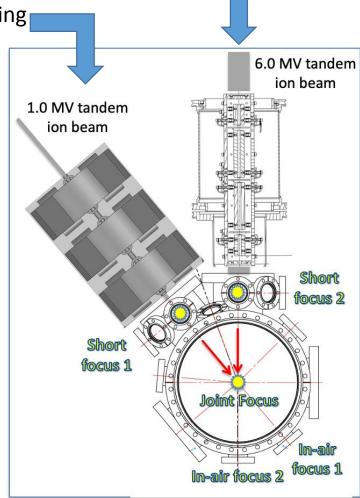


#### **Backup 1: RBI Short Term Upgrades**

#### Relevant upgrades of the RBI facility: 2022 – new dual microprobe:

- Two ion microbeams in the same time:
  - High LET ions from 6.0 MV for damaging or Single Event Effects
  - low LET (protons) from 1.0 MV for targeting coordinates and detector testing
- Electrostatic quadrupoles will enable focussing of higher LET ions:
  - Cions now 20 MeV, soon 25 MeV
  - Si ions now 25 MeV, soon 35 MeV
  - Au ions now 10 MeV, soon 50 MeV





#### **Backup 2: RBI Mid Term Upgrades**

# Relevant upgrades of the RBI facility: 2023/24 - transfer to the new hall:

- Old tandem van de Graaff to be replaced with modern 6.0 MV tandem
- Higher rigidity magnets (ME/q² up to 200 MeV) will enable higher LET heavy ions



